-				1		
PCN Number:	20180111003		PCN Date:	Janu	ary 19, 2018	
Title: Datasheet for						
<b>Customer Contact:</b>	PCN Manager			De	<b>pt:</b> Quality Service	es
Change Type:						
Assembly Site		Design			Wafer Bump Site	
Assembly Process		Data Sheet		44	Wafer Bump Material	
Assembly Materials		Part number	er change	44	Wafer Bump Process	
Mechanical Specific		Test Site		+ $+$ $+$	Wafer Fab Site	
Packing/Shipping/l	_abeling   I	Test Proces	SS	+ $+$ $+$	Wafer Fab Materials	
	Not	tification	n Details		Wafer Fab Process	
<b>Description of Chang</b>		cacioi	Details			
Texas Instruments Inco The product datasheet( The following change h	orporated is annous) is being update	ed as sum	marized belov			MP20
TEXAS INSTRUMENTS			SBO	S466A - [	DECEMBER 2009-REVISED OCTOB	ER 2017
Changes from Original (Dece	ember 2009) to Revisio	on A			Paç	je
					andards	
<ul> <li>Added body size information</li> </ul>	on to Device Information	n section				1
	•					
Updated Device Quiescent Current Over Temperature						
Reformatted Absolute Maximum Ratings table						
Changed Thermal Information table and added thermal information						
<ul> <li>Changed minimum temperature sensitivity value from –11.4 mV/°C to –12.2 mV/°C in Electrical Characteristics table 5</li> </ul>						
-					ectrical Characteristics table	
					EE	6
Added Functional Block diagram, key graphics on front page, typical application schematic, application curves, and updated layout images					8	
Reformatted equations in Transfer Function section					9	
Corrected Equation 2 in Transfer Function section					9	
Added copyright notices to Figure 15 and Figure 16					14	
·	lock Diagram uiescent Current Ov Figure 3, and Figur	ver Tempei	_	chang	ge for the following items:	:
Device Family		Change I	From:		Change To:	
TMP20		SBOS466			SBOS466A	
These changes may be	reviewed at the d	datasheet	links provided	j.		
http://www.ti.com/prod	duct/INA138					
Reason for Change:						
Added thermal metric specifications; Datasheet reformatting change.						
	<u> </u>				v (positive / negativ	e):
	Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):  No anticipated impact. There are no changes to the actual device.					
No anticipated impact. There are no changes to the actual device.						

Changes to product identification resulting from this PCN:					
None.					
Product Affected:					
TMP20AIDCKR	TMP20AIDCKT	TMP20AIDRLR	TMP20AIDRLT		

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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